



AF/HFW

IN THE U.S. PATENT AND TRADEMARK OFFICE

September 12, 2008

Applicants : Yoshio KAJIYA et al  
Title : METHOD OF PRODUCING CATHODE MATERIAL  
FOR LITHIUM SECONDARY CELL  
Serial No. : 10/521 370 Group: 1795  
Confirmation No.: 2268  
Filed : January 12, 2005 Examiner: Echelmeyer  
International Application No.: PCT/JP2003/002027  
International Filing Date : February 25, 2003  
Atty. Docket No.: 4402.P0666US  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**PETITION FOR TIME EXTENSION, AND CERTIFICATE OF MAILING**

Sir:

An Appellants' Brief on Appeal is enclosed.  
Pursuant to 37 CFR 1.136(a), please extend the shortened  
period for response by two months. The extension fee is:  
[X] \$460.00 (37 CFR 1.17)

A check for \$970.00 is enclosed to cover fees.

If this Petition is not timely received, please extend the  
shortened period an additional month. Please credit any over-  
payment, or charge any additional fee required by this  
Petition, to Deposit Account No. 06-1382. A duplicate of this  
Petition is enclosed.

Respectfully submitted,

IN DUPLICATE  
TFC/smd

  
Terryence F. Chapman

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John A. Waters	Reg. No. 24 802
Brian R. Tumm	Reg. No. 36 328
Donald J. Wallace	Reg. No. 43 977
Dale H. Thiel	Reg. No. 24 323
Sidney B. Williams, Jr.	Reg. No. 24 949
Heon Jekal	Reg. No. L0379*

\*limited recognition number

09/16/2008 HDESTA1 00000033 10521370

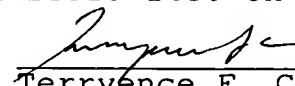
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Appellants' Brief on Appeal dated September 12, 2008

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Terryence F. Chapman



## PATENT APPLICATION

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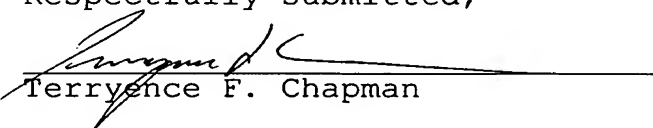
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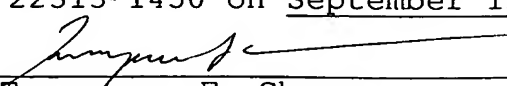
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